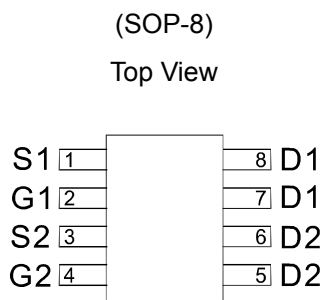


## N and P- Channel 30-V (D-S) MOSFET

### GENERAL DESCRIPTION

The ME4542 is the N and P Channel logic enhancement mode power field effect transistors are produced using high cell density , DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other battery powered circuits where high-side switching, and low in-line power loss are needed in a very small outline surface mount package.

### PIN CONFIGURATION

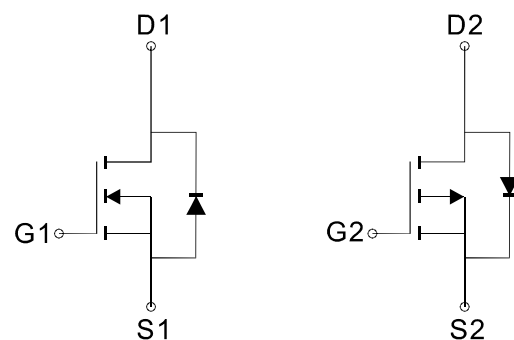


### FEATURES

- $R_{DS(ON)} \leq 25m\Omega @ V_{GS}=10V$  (N-Ch)
- $R_{DS(ON)} \leq 40m\Omega @ V_{GS}=4.5V$  (N-Ch)
- $R_{DS(ON)} \leq 35m\Omega @ V_{GS}=-10V$  (P-Ch)
- $R_{DS(ON)} \leq 58m\Omega @ V_{GS}=-4.5V$  (P-Ch)
- Super high density cell design for extremely low  $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability

### APPLICATIONS

- Power Management
- DC/DC Converter
- LCD TV & Monitor Display inverter
- CCFL inverter
- LCD Display inverter



N-Channel MOSFET    P-Channel MOSFET

Ordering Information: ME4542 (Pb-free)

ME4542-G (Green product-Halogen free)

### Absolute Maximum Ratings (TA=25°C Unless Otherwise Noted)

Parameter	Symbol	N-Channel	P-Channel	Unit
		Maximum Ratings	Maximum Ratings	
Drain-Source Voltage	$V_{DS}$	30	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	$\pm 20$	
Continuous Drain Current	$I_D$	$T_A=25^\circ C$	-6	A
		$T_A=70^\circ C$	-4.8	
Pulsed Drain Current	$I_{DM}$	28	-24	
Maximum Power Dissipation	$P_D$	$T_A=25^\circ C$	2	W
		$T_A=70^\circ C$	1.3	
Operating Junction Temperature	$T_J$	-55 to 150		$^\circ C$
Thermal Resistance-Junction to Ambient *	$R_{\theta JA}$	62.5	62.5	$^\circ C/W$

\*The device mounted on 1in2 FR4 board with 2 oz copper

## N and P- Channel 30-V (D-S) MOSFET

Electrical Characteristics (TA=25°C Unless Otherwise Specified)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>STATIC</b>						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250 μA V <sub>GS</sub> =0V, I <sub>D</sub> =-250 μA	N-Ch P-Ch	30 -30		V
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250 μA V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250 μA	N-Ch P-Ch	1.0 -1.0	3.0 -3.0	V
I <sub>GSS</sub>	Gate Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V	N-Ch P-Ch		±100 ±100	nA
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V V <sub>DS</sub> =-30V, V <sub>GS</sub> =0V	N-Ch P-Ch		1 -1	μA
R <sub>DS(ON)</sub>	Drain-Source On-State Resistance <sup>a</sup>	V <sub>GS</sub> =10V, I <sub>D</sub> = 6.7A V <sub>GS</sub> =-10V, I <sub>D</sub> = -6.1A	N-Ch P-Ch	21 30	25 35	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> = 5.0A V <sub>GS</sub> =-4.5V, I <sub>D</sub> = -5.0A	N-Ch P-Ch	32 48	40 58	
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =1.7A, V <sub>GS</sub> =0V I <sub>S</sub> =-1.7A, V <sub>GS</sub> =0V	N-Ch P-Ch	0.8 -0.8	1.2 -1.2	V
<b>DYNAMIC</b>						
Q <sub>g</sub>	Total Gate Charge	N-Channel V <sub>DS</sub> =15V, V <sub>GS</sub> =10V, I <sub>D</sub> =6.7A P-Channel V <sub>DS</sub> =-15V, V <sub>GS</sub> =-10V, I <sub>D</sub> =-6.1A	N-Ch P-Ch	12 21		nC
Q <sub>gs</sub>	Gate-Source Charge		N-Ch P-Ch	2 4		
Q <sub>gd</sub>	Gate-Drain Charge		N-Ch P-Ch	2.5 6		
C <sub>iss</sub>	Input Capacitance	N-Channel V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1MHz P-Channel V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1MHz	N-Ch P-Ch	360 840		pF
C <sub>oss</sub>	Output Capacitance		N-Ch P-Ch	70 120		
C <sub>rss</sub>	Reverse Transfer Capacitance		N-Ch P-Ch	17 32		
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz	N-Ch P-Ch	0.5 5.5		Ω
t <sub>d(on)</sub>	Turn-On Delay Time	N-Channel V <sub>DD</sub> =15V, R <sub>L</sub> =15Ω I <sub>D</sub> =1A, V <sub>GEN</sub> =10V, R <sub>G</sub> =6Ω  P-Channel V <sub>DD</sub> =-15V, R <sub>L</sub> =15Ω I <sub>D</sub> =-1A, V <sub>GEN</sub> =-10V, R <sub>G</sub> =6Ω	N-Ch P-Ch	9.3 32		ns
t <sub>r</sub>	Turn-On Rise Time		N-Ch P-Ch	14 13		
t <sub>d(off)</sub>	Turn-Off Delay Time		N-Ch P-Ch	32 58		
t <sub>f</sub>	Turn-Off Fall Time		N-Ch P-Ch	3.2 6.8		

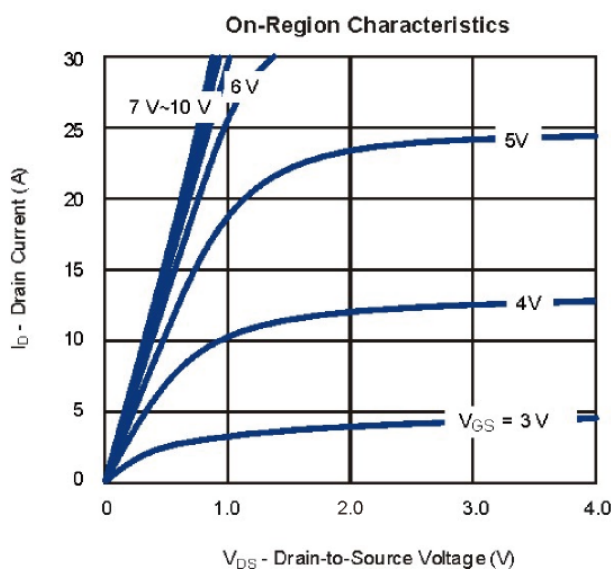
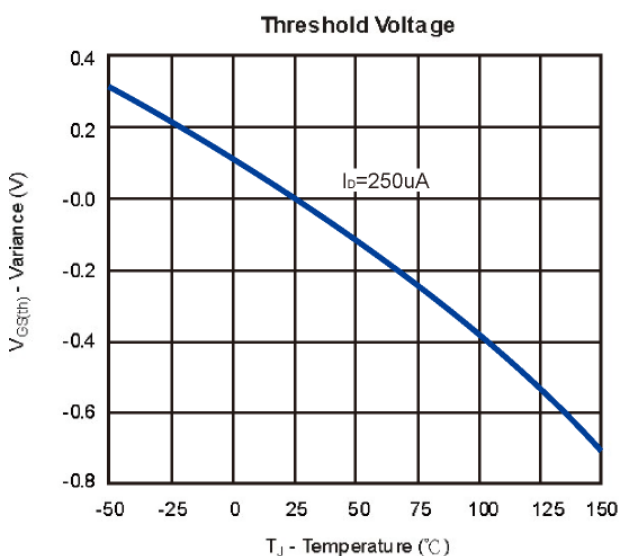
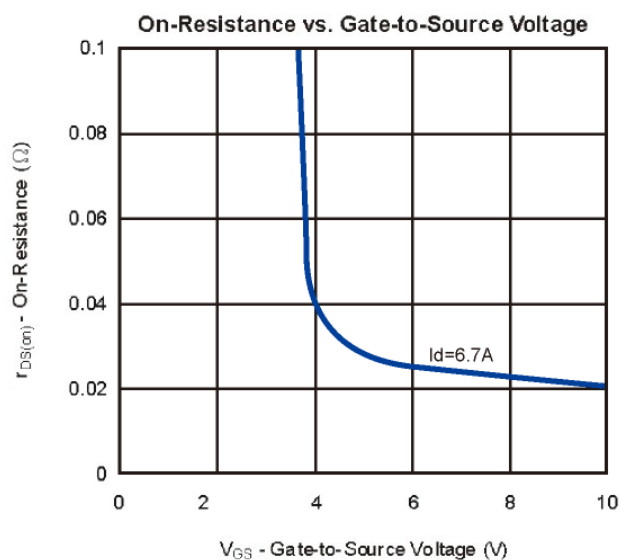
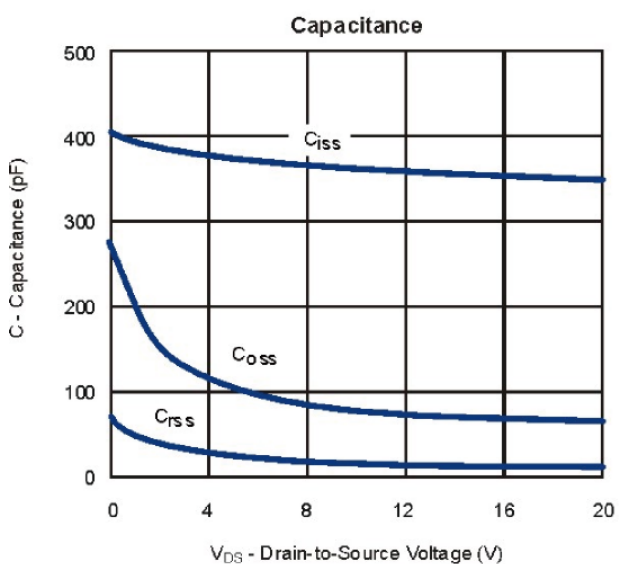
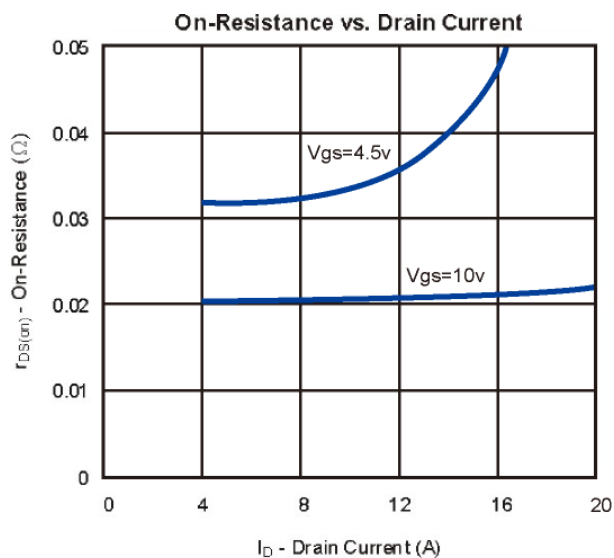
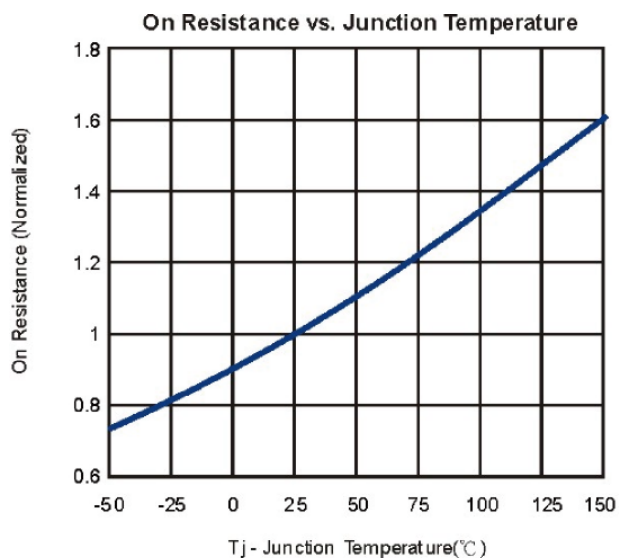
Notes: a. Pulse test; pulse width ≤ 300us, duty cycle ≤ 2%

b. Matsuki Electric/ Force mos reserves the right to improve product design, functions and reliability without notice.

**N and P- Channel 30-V (D-S) MOSFET**

**Typical Characteristics (T<sub>J</sub> =25°C Noted)**

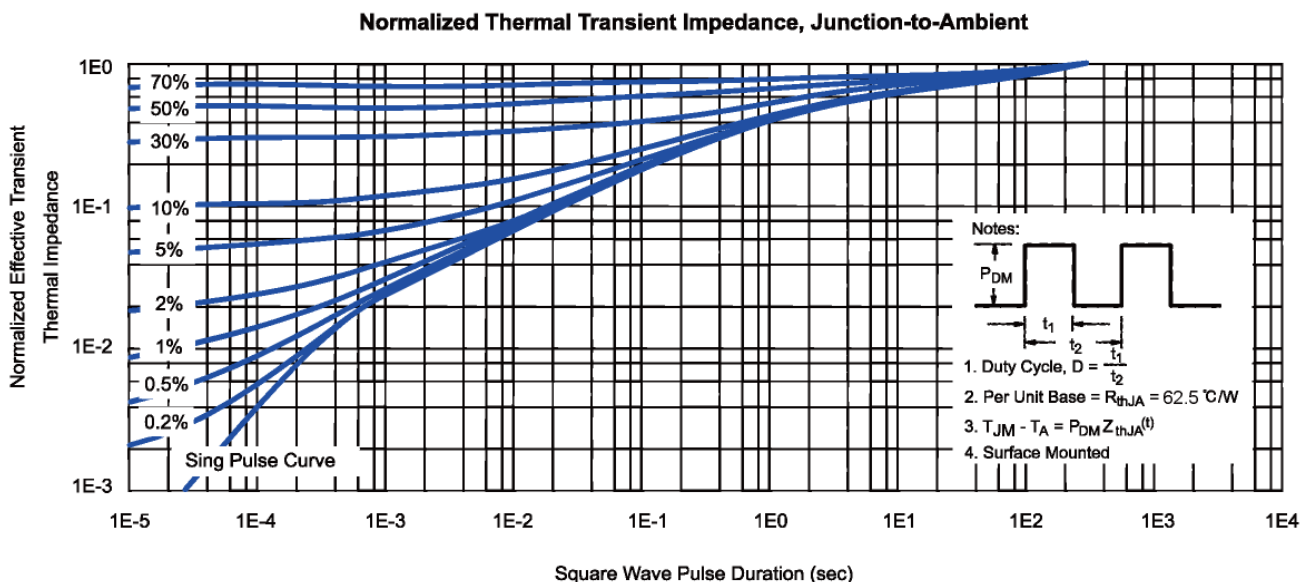
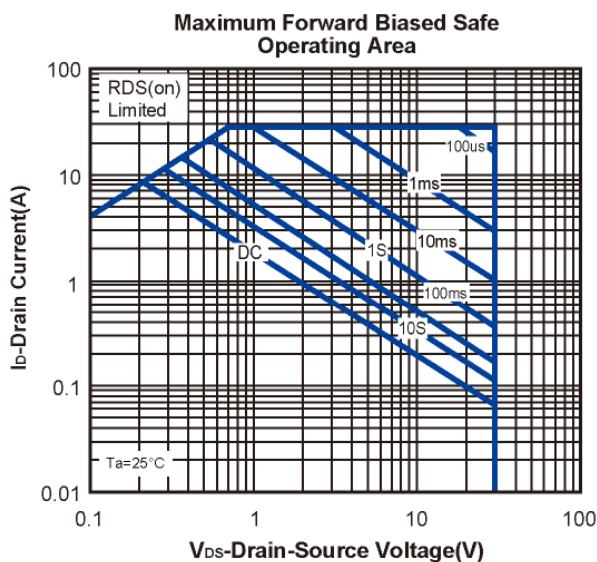
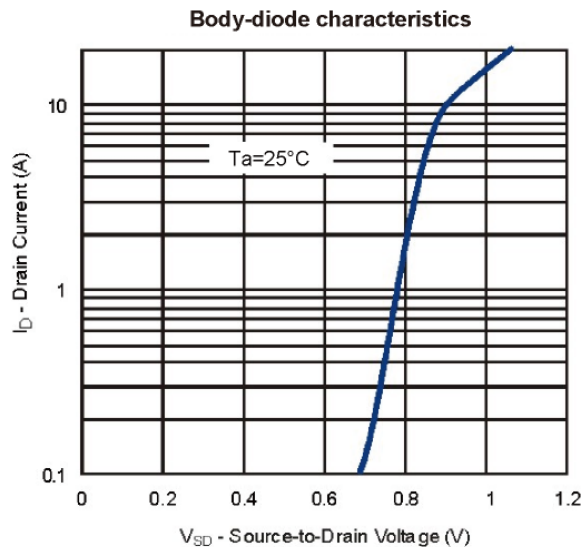
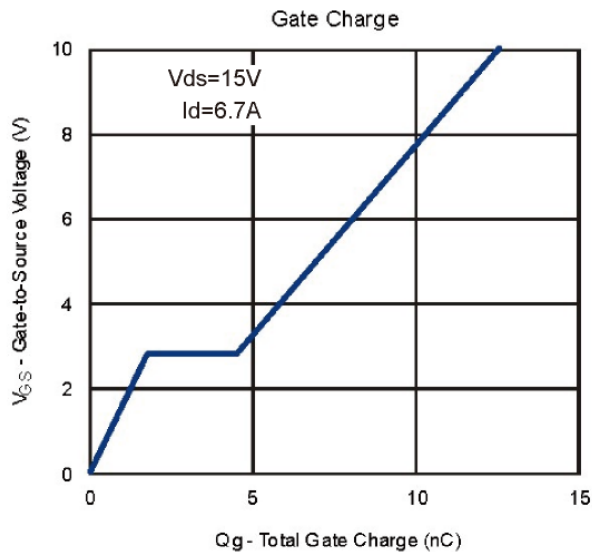
**N-CHANNEL**



**N and P- Channel 30-V (D-S) MOSFET**

**Typical Characteristics (T<sub>J</sub> = 25°C Noted)**

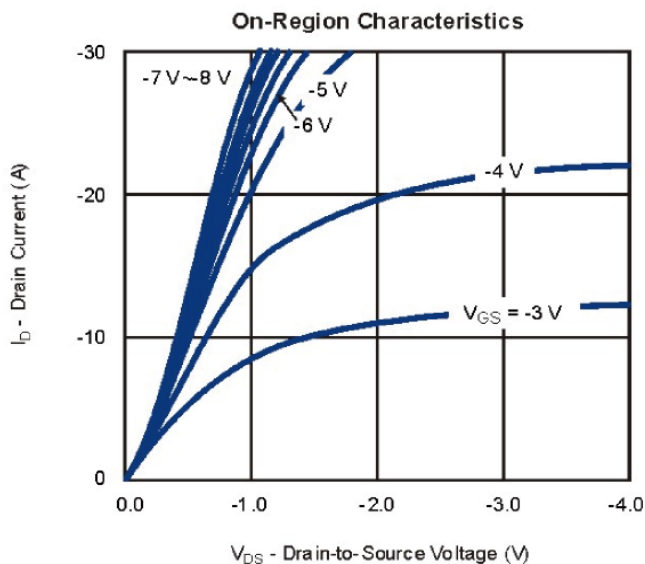
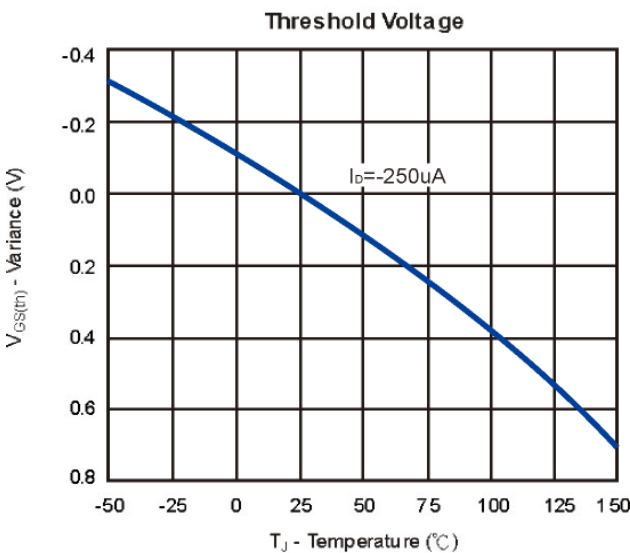
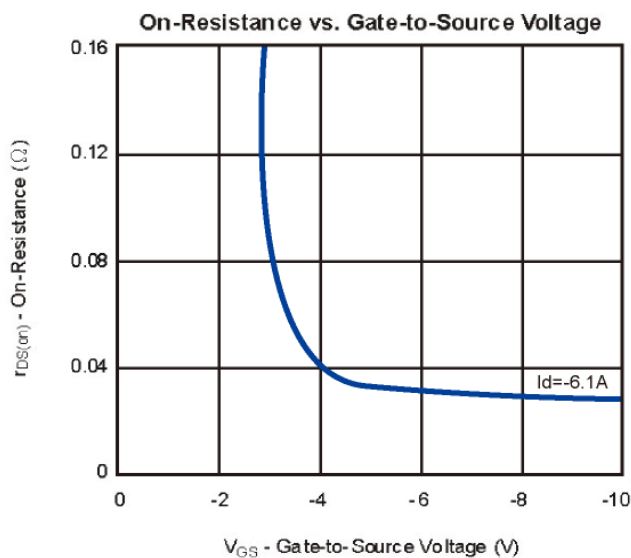
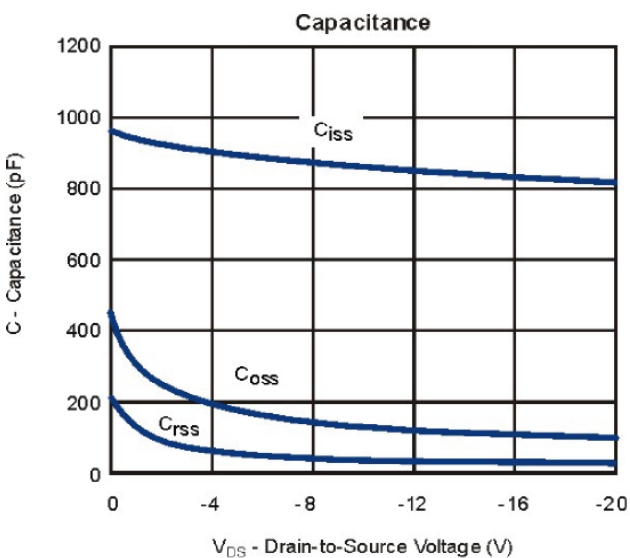
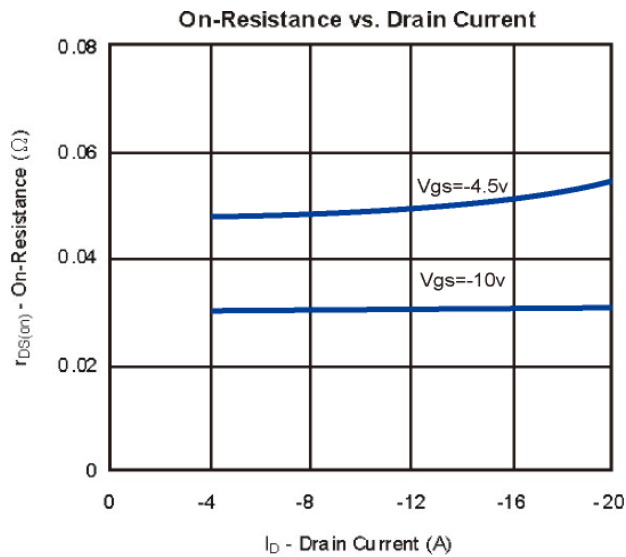
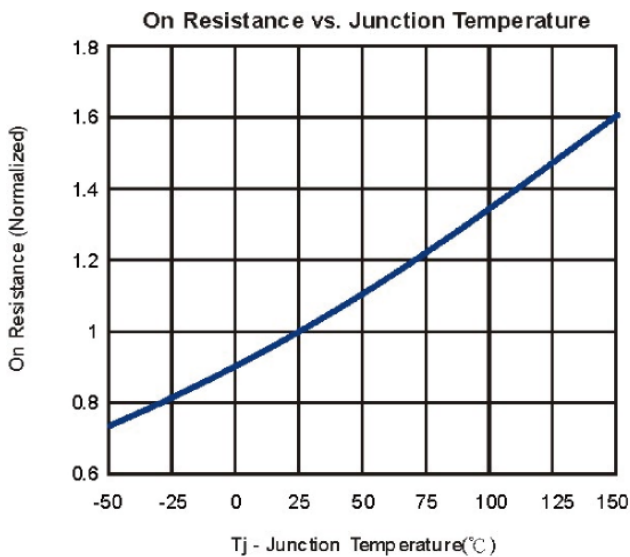
**N-CHANNEL**



**N and P- Channel 30-V (D-S) MOSFET**

**Typical Characteristics (T<sub>J</sub> =25°C Noted)**

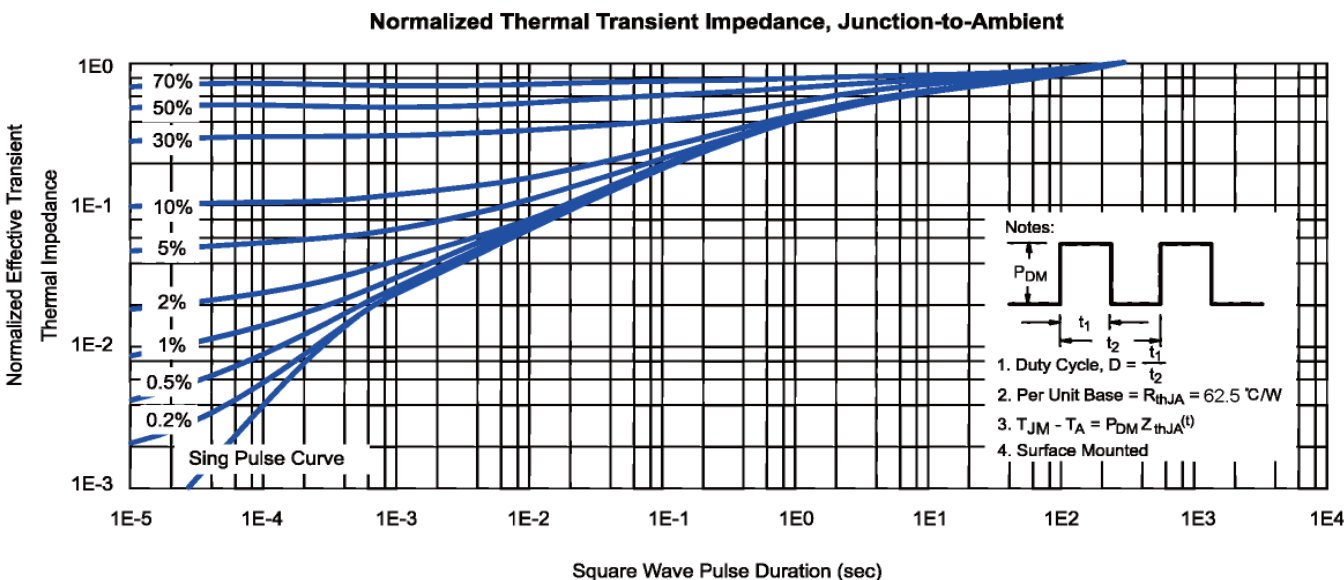
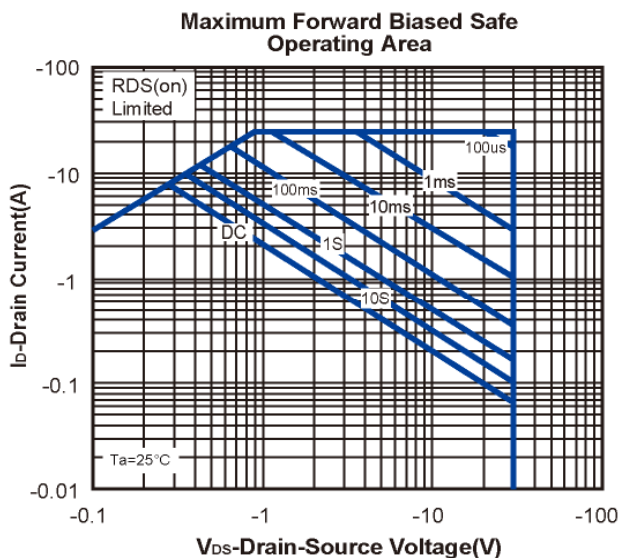
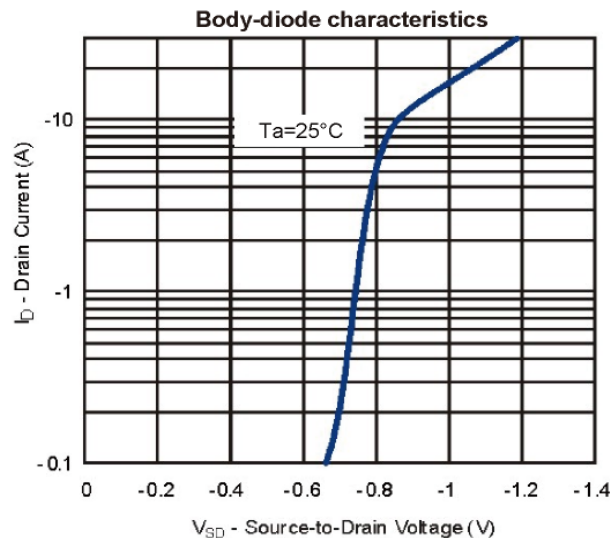
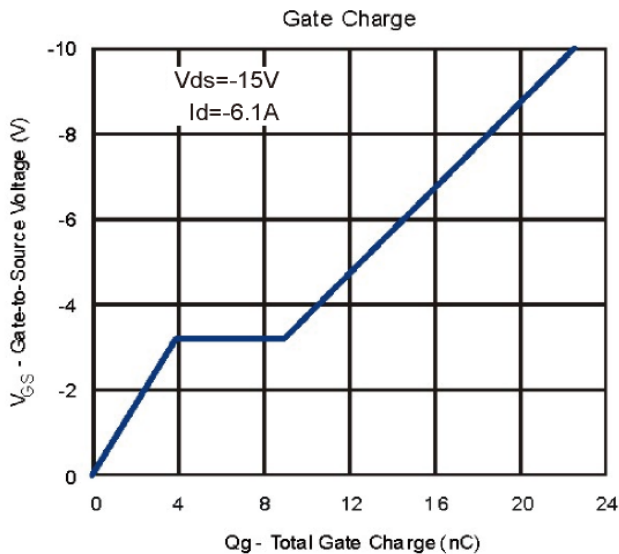
**P-CHANNEL**



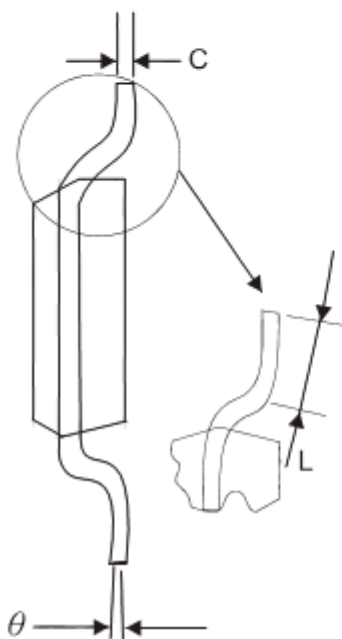
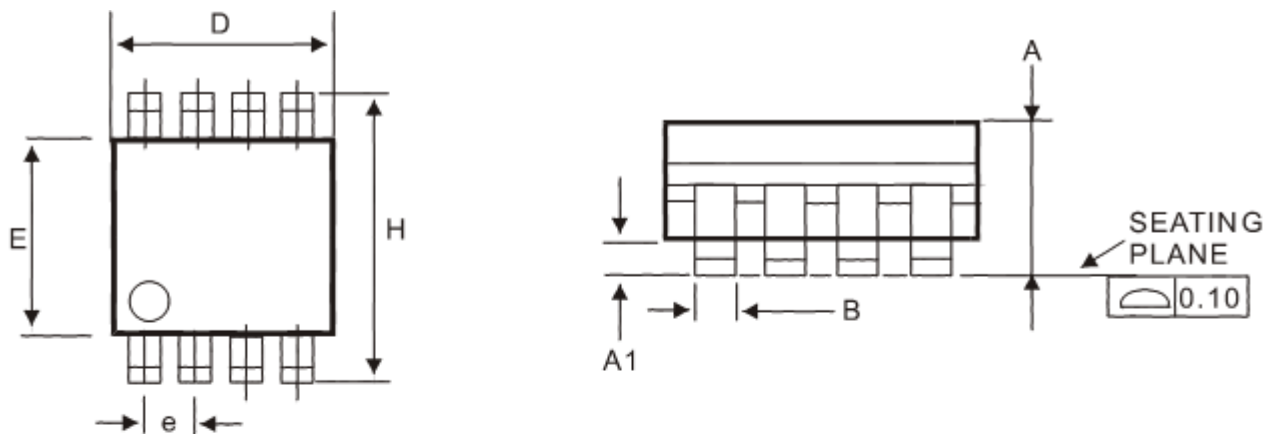
**N and P- Channel 30-V (D-S) MOSFET**

**Typical Characteristics (T<sub>J</sub> =25°C Noted)**

**P-CHANNEL**



**SOP-8 Package Outline**



DIM	MILLIMETERS (mm)	
	MIN	MAX
A	1.35	1.75
A1	0.10	0.25
B	0.35	0.49
C	0.18	0.25
D	4.80	5.00
E	3.80	4.00
e	1.27 BSC	
H	5.80	6.20
L	0.40	1.25
$\theta$	0°	7°

Note: 1. Refer to JEDEC MS-012AA.

2. Dimension "D" does not include mold flash, protrusions or gate burrs . Mold flash, protrusions or gate burrs shall not exceed 0.15 mm per side.